5

5.17

A Si p^+ -n junction has a donor doping of $5\times 10^{16}~cm^{-3}$ on the n side and a cross-sectional area of $10^{-3}~cm^2$. If $\tau_p=1~\mu s$ and $D_p=10~cm^2/s$, calculate the current with a forward bias of 0.5~V at 300~K.

$$egin{aligned} imes ext{Answer} &igsim p_n = rac{n_i^2}{N_d} \ L_p = \sqrt{ au_p D_p} \ I_p = q A rac{D_p}{L_p} p_n (e^{qV/kT} - 1) \ I_p = q A rac{D_p}{\sqrt{ au_p D_p}} rac{n_i^2}{N_d} (e^{qV/kT} - 1) \ I_p = q A rac{D_p}{\sqrt{ au_p D_p}} rac{n_i^2}{N_d} (e^{qV/kT} - 1) \ I pprox I_p = 5.513 imes 10^{-7} A \end{aligned}$$

5.19

a

A Si p^+ -n junction $10^{-2}\ cm^2$ in area has $N_d=10^{15}\ cm^{-3}$ doping on the n side. Calculate the junction capacitance with a reverse bias of $10\ V$.

$$egin{aligned} & extstyle extstyle extstyle Answer \ C_j &= rac{\epsilon_r \epsilon_0 A}{W} \ W &= \sqrt{rac{2\epsilon(V_0 - V)}{q} \left(rac{N_a + N_d}{N_a N_d}
ight)} pprox \sqrt{rac{2\epsilon V_r}{q} \left(rac{1}{N_d}
ight)} \ C_j &= A\sqrt{rac{q\epsilon_r \epsilon_0 N_d}{2V_r}} \ C_j &= 2.890 imes 10^{-11} \ F \end{aligned}$$

b

An abrupt p^+ -n junction is formed in Si with a donor doping of $N_d=10^{15}\ cm^{-3}$. What is the depletion region thickness W just prior to avalanche breakdown?

✓ Answer

I could not find the formula for anything related to avalanche breakdown on the slides or in the text, but the W region should increase in size, but with a strong enough field that a multiplicative effect is realized in electrons with EHPs.

5.24

A Si p-n junction with cross-sectional area $A=0.001\ cm^2$ is formed with $N_a=10^{15}\ cm^{-3}$ and $N_d=10^{20}\ cm^{-3}$.

Calculate:

a

Contact potential V_0 .

```
m{\mathcal{V}}_0 = rac{kT}{q} \mathrm{ln} \left(rac{N_a N_d}{n_i^2}
ight) \ V_0 = 0.8735512160281839 \ V
```

b

Space-charge width at equilibrium (zero bias).

```
egin{aligned} \checkmark AnswerW=\sqrt{rac{2\epsilon(V_0-V)}{q}\left(rac{N_a+N_d}{N_aN_d}
ight)} \ W=1.067859223747202~\mu m \end{aligned}
```

C

Current with a forward bias of 0.7~V. Assume $\mu_n=1500~cm^2/Vs$, $\mu_p=450~cm^2/Vs$, and $\tau_n=\tau_p=2.5~ms$. Which carries most of the current, electrons or holes, and why? If you wanted to double the electron current, what should you do?

$$egin{aligned} \checkmark$$
 Answer $I_p = qArac{D_p}{L_p}p_n(e^{qV/kT}-1) \ I_n = qArac{D_n}{L_n}n_p(e^{qV/kT}-1) \ L = \sqrt{D au} \ rac{kT}{q} = rac{D}{\mu} \ p_n = rac{n_i^2}{N_d} \ n_p = rac{n_i^2}{N_a} \end{aligned}$

$$egin{align} I_p &= q A \sqrt{rac{kT \mu_p}{q au_p}} rac{n_i^2}{N_d} (e^{qV/kT} - 1) \ I_n &= q A \sqrt{rac{kT \mu_n}{q au_n}} rac{n_i^2}{N_a} (e^{qV/kT} - 1) \ I_p &= 1.344 imes 10^{-8} \ A \ I_n &= 0.002453 \ A \ \end{align}$$

 $I_p > I_n$ therefore the holes carry more current.

$$I=I_n=2.453\ mA$$

I would decrease N_d

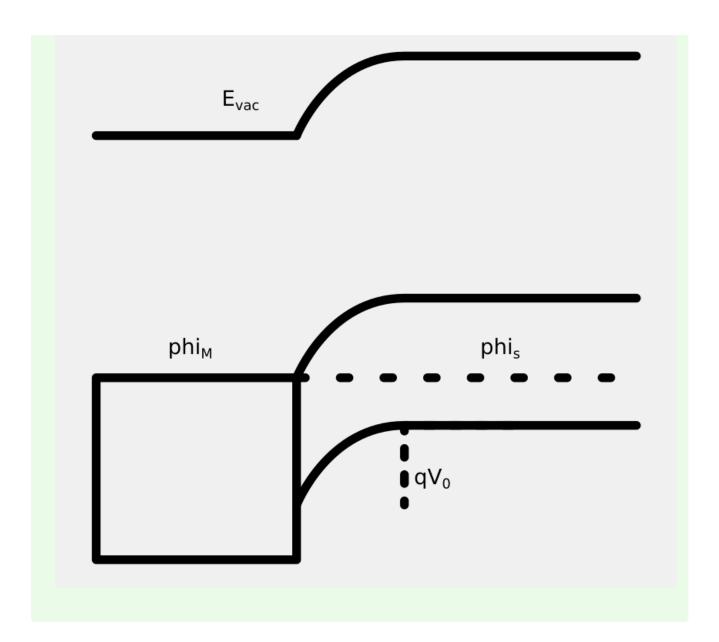
5.45

A shottky barrier is formed between a metal having a work function of 4.3~eV and p-type Si (electron affinity = 4~eV). The acceptor doping in the Si is $10^{17}~cm^{-3}$.

a

Draw the equilibrium band diagram, showing a numerical value for qV_0 .

$egin{aligned} extstyle extstyle Answer \ \phi_M &= 4.3 \ eV \ \chi_{si} &= 4 \ eV \ N_a &= 10^{17} \ cm^{-3} \ \end{aligned} \ egin{aligned} p_0 &= n_i e^{(E_i - E_F)/kT} \ E_i - E_F &= kT \ln \left(rac{p_0}{n_i} ight) \ E_i - E_F &= 0.406957131059819 \ eV \ \end{aligned} \ \phi_s &= E_g + \chi_{si} + E_F - E_V &= 4.71 \ eV \ \phi_s &> \phi_M \ \end{aligned} \ V_0 &= \phi_s - \phi_M &= 0.41 \ eV \end{aligned}$



b

Draw the band diagram with $0.3\ V$ forward bias. Repeat for $2\ V$ reverse bias.

✓ Answer

The barrier height would change depending on the bias

With a $0.3\ V$ forward, we would have $qV_0=0.11\ eV$

With a $2\ V$ reverse, we would have $qV_0=2.41\ eV$